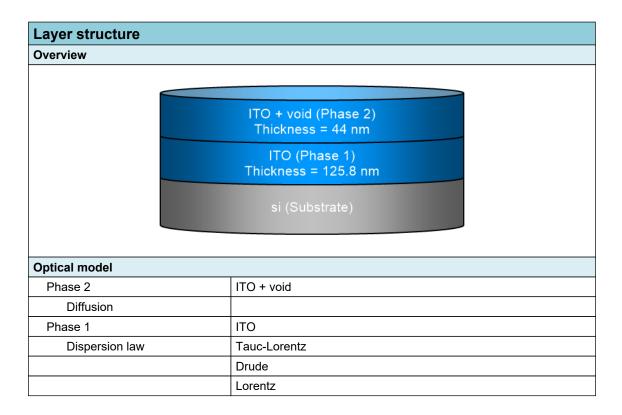


SEA regression report summary

Sample ID 001e-int-i 70° 1

Details				
Software and regression log				
Software about	Semilab - Spectroscopic Ellipsometry Analyzer - SEA			
Software version	1.7.1			
Officially licensed to	MIT			
Operator	operator			
Date and time of regression	14-07-2021 14:05			
Comments				





Regression results

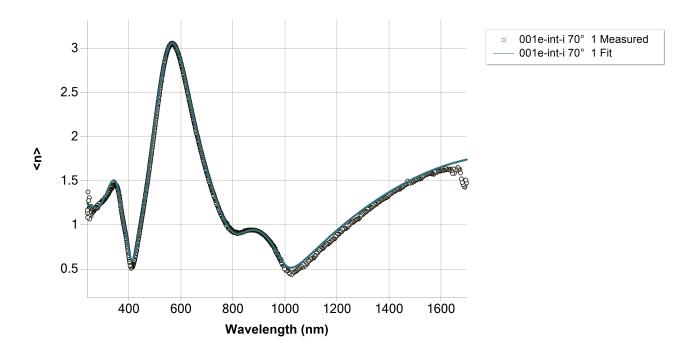
Measurement information						
Measurement file path	C:\Users\emmabat\ito	C:\Users\emmabat\ito-si\001e-int-i.smdx				
Angle of Incidence	70°					
Regression details						
Regression 1 (EllipsoReflectance)						
Wavelength range	239.84 - 1698.83 nm	239.84 - 1698.83 nm				
Angle of Incidence	70°	70°				
Fit to	<n>, <k></k></n>					
Angular Aperture	0°	0°				
Fit algorithm	LMA					
Results						
Parameters	Value	Fitted	2 σ confidence limit	Unit		
Model						
AOI Shift	0			0		
Angular Aperture	0			0		
Phase 2 (ITO + void)				_		
Thickness	44.039	Х	0.27244	nm		
Depolarization coefficient	0.33333					
Concentration 1	0.5					
Concentration 2	0.5					
Phase 1 (ITO)						
Thickness	125.839	Х	0.73897	nm		
A (eV)	499.9547			eV		
E0 (eV)	6.0053			eV		
C (eV)	56.35877	Х	0.64192	eV		
Eg (eV)	2.51989	Х	0.025488	eV		
E_p (eV)	1.14766	Х	0.0087536	eV		
E_Γ (eV)	0.42362	Х	0.018772	eV		
f	0.14838	Х	0.015792			
E0 (eV)	2.70255	Х	0.082117	eV		
Γ (eV)	1.3114	Х	0.13246	eV		
Eps_inf	0					
Derived parameters	Value					
Phase 2 (ITO + void)						
n @ 632.8 nm	1.4699					
k @ 632.8 nm	0.0253					
Phase 1 (ITO)						
n @ 632.8 nm	1.992					
k @ 632.8 nm	0.0553					
Substrate (si)						
n @ 632.8 nm	3.8811					
k @ 632.8 nm	0.0195					
Drude derived parameters	Value			Unit		
Phase 1 (ITO)						
Conductivity (S/m)	4.1824E+04 ± 2491.3814			S/m		

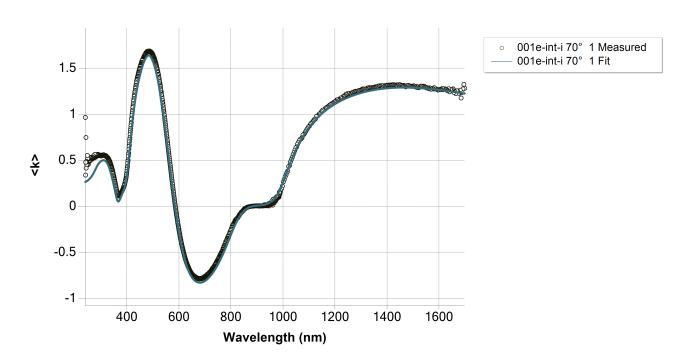


Resistivity (mΩ.cm)	2.3909 ± 0.1424	mΩ.cm		
Resistance (Ω/sq)	190.0002 ± 12.4336	Ω/sq		
N type dopant concentration (at/cm3)	2.3881E+20 ± 3.643E+18	at/cm3		
P type dopant concentration (at/cm3)	3.5344E+20 ± 5.3916E+18	at/cm3		
N type dopant mobility (cm2/Vs)	10.9312 ± 0.6722	cm2/Vs		
P type dopant mobility (cm2/Vs)	7.3859 ± 0.4542	cm2/Vs		
Fit quality				
R^2	0.99379			
RMSE	0.05722			



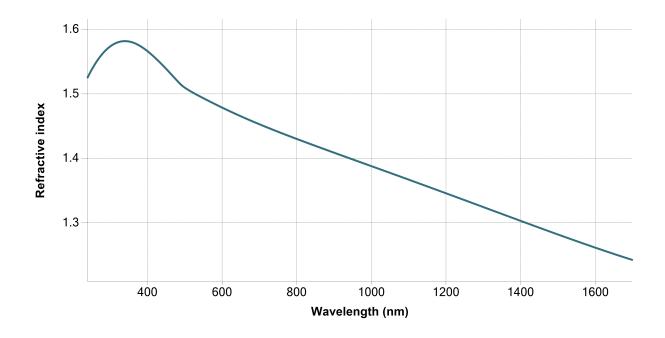
Regression graphs

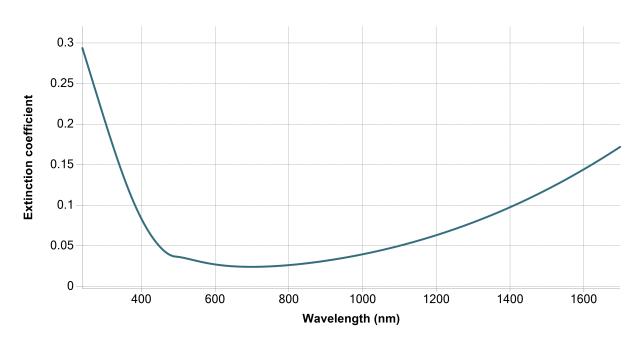






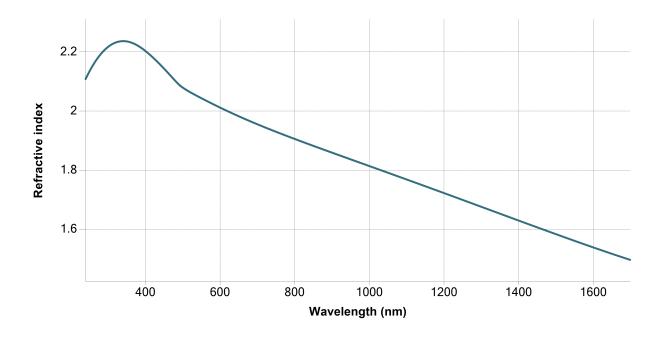
Phase 2 (ITO + void) - Dispersion graphs

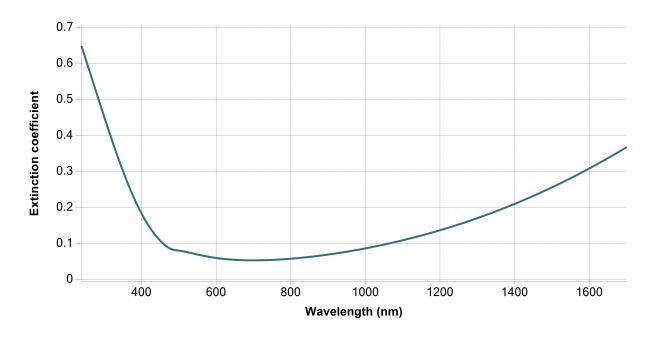






Phase 1 (ITO) - Dispersion graphs







Substrate (si) - Dispersion graphs







Correlation coefficients	
Ph2 - ITO + void - Thickness Ph1 - ITO - Thickness	-0.4129
Ph2 - ITO + void - Thickness Ph1 - Tauc-Lorentz[1] - C (eV)	0.1718
Ph2 - ITO + void - Thickness Ph1 - Tauc-Lorentz[1] - Eg (eV)	-0.2134
Ph2 - ITO + void - Thickness Ph1 - Drude[2] - E_p (eV)	-0.3635
Ph2 - ITO + void - Thickness Ph1 - Drude[2] - E_Γ (eV)	0.0242
Ph2 - ITO + void - Thickness Ph1 - Lorentz[3] - f	-0.1869
Ph2 - ITO + void - Thickness Ph1 - Lorentz[3] - E0 (eV)	-0.1549
Ph1 - ITO - Thickness Ph1 - Tauc-Lorentz[1] - C (eV)	-0.0325
Ph1 - ITO - Thickness Ph1 - Tauc-Lorentz[1] - Eg (eV)	0.5457
Ph1 - ITO - Thickness Ph1 - Drude[2] - E_p (eV)	0.3295
Ph1 - ITO - Thickness Ph1 - Drude[2] - E_Γ (eV)	0.2859
Ph1 - ITO - Thickness Ph1 - Lorentz[3] - f	0.5457
Ph1 - ITO - Thickness Ph1 - Lorentz[3] - E0 (eV)	0.4986
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Tauc-Lorentz[1] - Eg (eV)	-0.8245
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Drude[2] - E_p (eV)	-0.4295
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Drude[2] - Ε_Γ (eV)	0.4812
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Lorentz[3] - f	-0.7094
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Lorentz[3] - E0 (eV)	-0.7641
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Drude[2] - E_p (eV)	0.4028
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Drude[2] - Ε_Γ (eV)	-0.2442
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Lorentz[3] - f	0.9321
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Lorentz[3] - E0 (eV)	0.9576
Ph1 - Drude[2] - E_p (eV) Ph1 - Drude[2] - Ε_Γ (eV)	-0.0058
Ph1 - Drude[2] - E_p (eV) Ph1 - Lorentz[3] - f	0.314
Ph1 - Drude[2] - E_p (eV) Ph1 - Lorentz[3] - E0 (eV)	0.3129
Ph1 - Drude[2] - Ε_Γ (eV) Ph1 - Lorentz[3] - f	-0.3625
Ph1 - Drude[2] - E_Γ (eV) Ph1 - Lorentz[3] - E0 (eV)	-0.2774
Ph1 - Lorentz[3] - f Ph1 - Lorentz[3] - E0 (eV)	0.9645